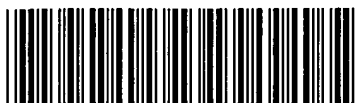


**Search Notes**

Application/Control No.

10/611,896

Examiner

Thien F. Tran

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2811

**SEARCHED**

Class	Subclass	Date	Examiner
257	52,57 59-61 72	5/4/2005	TT
Above	updated	10/28/2005	TT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR